## **Best Paper Awards**

Each year the Design, Automation and Test in Europe Conference presents awards to the authors of the most outstanding papers of the previous year's conference. The selection is performed by an award committee, based on the results of the reviewing process, the quality of the final paper and the quality of the presentation.

The paper selected as the most outstanding is:

Run-Time Deadlock Detection in Networks-on-Chip Using Coupled Transitive Closure Networks

by R Al-Dujaily, T Mak, F Xia and A Yakovlev, University of Newcastle, UK

The paper selected as the most outstanding IP is:

A Fault Tolerant Deadlock Free Adaptive Routing for On-Chip Interconnects

by F Chaix, N-E Zergainoh and M Nicolaidis, TIMA Laboratory, France and D Avresky, IRIANC, FRance

Congratulations to the winners!